Nanofocus Electron Sources

Products

- RHEED
- AUGER / XPS / EELS / REELS
- Electron Sources
  - General Purpose Electron Sources
  - Microfocus and Nanofocus Electron Sources
    - EM-503
    - EM-506
    - EM-802
    - EF-1005
    - EF-1201
    - EF-1202
    - **EF-15005**
  - Electron Flood Sources
  - High Energy Small Focus Electron Sources
  - High Beam Power Electron Sources
  - Low Energy Electron

EF-15005

This electron gun column is designed to generate a very small spot in the nm range. It is also available as part of a complete scanning electron imaging package (SEM-package).

Key features

- Beam size (min.) <85 nm at max energy and 12 mm working distance
- Energy range 200 eV – 15 keV
- Beam current (max.) 1 µA

Characteristics

- Working Distance (WD) 10 mm – 50 mm
- Optimum WD 12 mm nominal
- Basic beam blanking (optional)
- Beam blanking, external (optional)
- Beam pulsing (optional)
- Computer control (optional)
- Magnetic shielding (optional)
- Beam scanning (optional)
- Microprocessor controlled beam current regulation (optional)
- Remote control

Not all parameters can be reached simultaneously. Above specifications may change without notice. Pictures / diagrams for reference only.

Typical Applications

AES- Depth profiling

Related Products

Filaments

Sources
- Electron Sources for RHEED
- Accessories for Electron Sources
- Ion Sources
- X-ray Source
- Energy Analyzers & Imaging Energy Filters
- Charged Particle Detectors
- PEEM & IEEM
- UHV-Systems for Surface Analysis
- Packages for Surface Analysis
- Data Acquisition & Instrument Control Software

Absorbent current EM (electron microscope)

Elastically scattered EM (electron microscope)

UHV Scanning Electron Microscopy (SEM)

Scanning Auger Microscopy (SAM)

Auger Electron Spectroscopy (AES)

Electron Energy Loss Spectroscopy (EELS) / Reflection Energy Energy Loss Spectroscopy (REELS)

Sample imaging

Electron Backscattered Diffraction (EBSD)

X-ray emission analyses

Pre-mounted, pre-aligned cathode units

Complete service kit

Diagnostic box

Scan amplifier

Faraday cups

Sample current measurement kit

Gun control module

AES and XPS energy spectrometers (ESA and DESA)

Secondary Electron Detectors (SED) for imaging

Scanning and imaging package (SEM Package)

EBSD energy filter and detector

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